

<b>Notice of References Cited</b>	Application/Control No. 10/026,176	Applicant(s)/Patent Under Reexamination SEO ET AL.	
	Examiner Brian L. Mutschler	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,011,580	04-1991	Pan et al.	205/118
	B	US-6,146,517	11-2000	Hoinkis, Mark D.	205/186
	C	US-6,162,365	12-2000	Bhatt et al.	216/13
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Copper Interconnect Films," <a href="http://www.appliedmaterials.com/products/copper_interconnect_films.html">http://www.appliedmaterials.com/products/copper_interconnect_films.html</a> (no date).
	V	"Polyimide," <a href="http://www.plasticsusa.com/tpi.html">http://www.plasticsusa.com/tpi.html</a> (no date).
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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